

<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/682,542	WEE ET AL.	
	Examiner	Art Unit	
	X. L. Bautista	2179	

**SEARCHED**

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search	12/23/2006	XB
Databases Searched: US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB		
Google Search		
IEEE Xplore Search		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner